Search Notes

Application/Control No.	Applicant(s)/Paten	olicant(s)/Patent under	
	Reexamination	•	
10/084,614	BIERLY ET AL.	:	
Examiner	Art Unit	•	

Jia W. Lu

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SEARCHED				
Class	Subclass	Date	Examiner	
375	219	6/15/2005	JL	
375	220	6/15/2005	JL	
375	221	6/15/2005	JL	
375	222	6/15/2005	JL	
375	223	6/15/2005	. JL	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
375	222	6/15/2005	JL	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	6/15/2005	JL	
INVENTORSHIP .	6/14/2005	JL	
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